



Characteristics	Symbols	MIL-STD-883 Test Method	Test Conditions Note 1	Limits		Units
				Min	Max	
High Level Input Voltage 2 (Noise Immunity) (Functional Test)	V_{IH2}	-	Verify Truth Table $V_{DD}=15V$, $V_{SS}=V_{EE}=0V$ Note 5	11	-	V
Threshold Voltage N-Channel	V_{THN}	-	INH Input and V_{EE} at Ground All Other Inputs: $V_{IN}=5V$ $V_{DD}=5V$, $I_{SS}=-10\mu A$	-0.7	-3	V
Threshold Voltage P-Channel	V_{THP}	-	INH Input at Ground All Other Inputs: $V_{IN}=-5V$ $V_{SS}=V_{EE}=-5V$, $I_{DD}=3.5\mu A$	0.7	3	V
Input Clamp Voltage 1, to V_{SS} , Control Inputs	V_{IC1}	-	I_{IN} (Under Test)=- $-100\mu A$ $V_{DD}=\text{Open}$, $V_{SS}=0V$ All Other Pins Open	-	-2	V
Input Clamp Voltage 2, to V_{DD} , Control Inputs	V_{IC2}	-	V_{IN} (Under Test)=6V $R=30k\Omega$, $V_{SS}=\text{Open}$ All Other Pins Open Note 6	3	-	V
Input Capacitance, Control Inputs	C_{IN}	3012	V_{IN} (Not Under Test)=0V $V_{DD}=V_{SS}=V_{EE}=0V$ $f=100\text{ kHz to }1\text{ MHz}$ Note 7	-	7.5	pF
Channel Capacitance, CH	C_{CH}	3012	V_{IN} (Not Under Test)=0V $V_{DD}=V_{SS}=V_{EE}=0V$ $f=100\text{ kHz to }1\text{ MHz}$ Note 7	-	7.5	pF
Channel Capacitance, XCOM, YCOM	C_{COM}	3012	V_{IN} (Not Under Test)=0V $V_{DD}=V_{SS}=V_{EE}=0V$ $f=100\text{ kHz to }1\text{ MHz}$ Note 7	-	30	pF
Propagation Delay Low to High \times , XCOM to XCH0	$t_{PLH\text{X}}$	3003	$V_{IN}(\text{COM})=\text{Pulse Generator}$ V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V$, $V_{IH}=5V$, $R_L=200k\Omega$ $V_{DD}=5V$, $V_{SS}=V_{EE}=0V$ Note 8	-	40	ns

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Propagation Delay High to Low X XCOM to CH0	t_{PHLX}	3003	$V_{IN}(COM)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V$, $V_{IH}=5V$, $R_L=200k\Omega$ $V_{DD}=5V$, $V_{SS}=V_{EE}=0V$ Note 8	-	40	ns
Propagation Delay Low to High 2 , A to YCOM (Channels ON)	t_{PLH2} t_{PZH1}	3003	$V_{IN}(A)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V$, $V_{IH}=5V$, $V_{IN}(CH)=0V$ and $5V$ and Open $R_L=10k\Omega$ $V_{DD}=5V$, $V_{SS}=V_{EE}=0V$ Note 8	-	720	ns
Propagation Delay High to Low 2 , A to YCOM (Channels ON)	t_{PHL2} t_{PHZ1}	3003	$V_{IN}(A)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V$, $V_{IH}=5V$, $V_{IN}(CH)=0V$ and $5V$ and Open $R_L=10k\Omega$ 300Ω $V_{DD}=5V$, $V_{SS}=V_{EE}=0V$ Note 8	-	720	ns
Output Enable Time High Impedance to High Output 2 , INH to YCOM	t_{PZH2}	3003	$V_{IN}(INH)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V$, $V_{IH}=5V$, $V_{IN}(CH)=5V$, $R_L=10k\Omega$ $V_{DD}=5V$, $V_{SS}=V_{EE}=0V$ Note 8	-	400	ns
Output Disable Time High Output to High Impedance 2 , INH to YCOM	t_{PHZ2}	3003	$V_{IN}(INH)$ =Pulse Generator V_{IN} (Remaining Inputs)=Truth Table $V_{IL}=0V$, $V_{IH}=5V$, $V_{IN}(CH)=5V$, $R_L=300\Omega$ $V_{DD}=5V$, $V_{SS}=V_{EE}=0V$ Note 8	-	400	ns

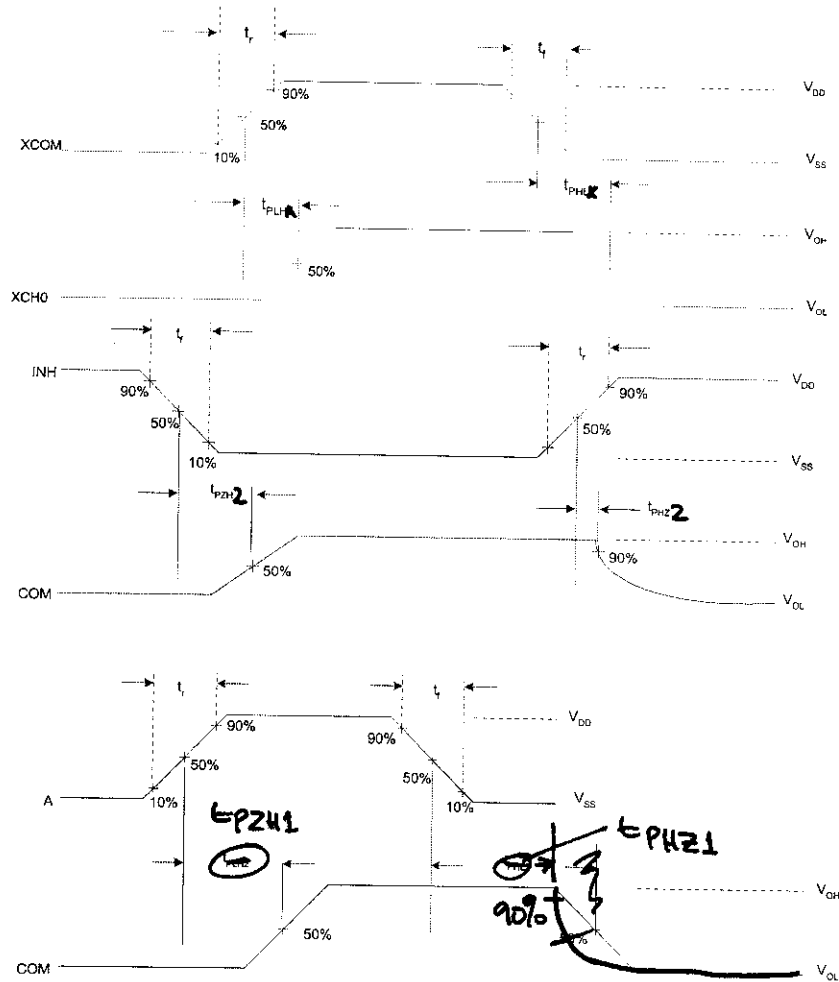
Output Enable
Time High
Impedance to
High Output 1,
A to YCOM

Output Disable
Time High Output
to High
Impedance 1,
A to YCOM

2.3.2

High and Low Temperatures Electrical Measurements

The measurements shall be performed at $T_{amb}=+125 (+0 -5) ^\circ C$ and $T_{amb}=-55(+5-0)^\circ C$.



2.4

PARAMETER DRIFT VALUES

Unless otherwise specified, the measurements shall be performed at $T_{amb} = +22 \pm 3^{\circ}C$.

The test methods and test conditions shall be as per the corresponding test defined in Room Temperature Electrical Measurements.

The drift values (Δ) shall not be exceeded for each characteristic specified. The corresponding absolute limit values for each characteristic shall not be exceeded.